

Brief text for the class of

## **“Pump and probe technique for picosecond time-resolved x-ray diffraction”**

- Two-day program at BL19LXU at the Cheiron School -

### **1. Introduction**

#### **1-1. Purpose**

The pulsed nature of the synchrotron radiation (SR) and the synchronization technique between SR pulse and ultrashort laser pulse enable us to make pump and probe measurements with 40 ps time resolution. The time resolved x-ray diffraction experiments will be demonstrated for the lattice dynamics of a single semiconductor crystal. The course may help you with starting the picosecond time-resolved experiments at your stations for investigation on fast structural dynamics.

#### **1-2. Objectives**

When a surface of GaAs single crystal is irradiated by a femtosecond pulse laser, the lattice expands with a response time of a few hundreds of ps. To observe the fast lattice response, a stroboscopic method in X-ray diffraction, i.e., laser-pump and SR-probe method is performed in the SPring-8 beamline.

### **2. Experimental apparatus and equipments prepared**

#### **2-1. The hard X-ray beamline BL19LXU**

The course will be opened at the beamline BL19LXU which can produce the most intense X-ray beam in the world at present. The SR beam generated by the 25 m-long undulator is guided to the experimental hutches through a Si 111 double-crystal monochromator (See ref. 1). The X-ray time-structure is determined by the electron bunches in the storage ring. The electron bunches have the pulse width of about 40 ps at full width at half maximum (FWHM), with a repetition rate of 1 MHz to 509 MHz. The repetition rate can be controlled by the ring operation with preferable filling pattern. In the class, the filling pattern operated is slightly complicated, which is called “hybrid mode”, to gain the bunch current for particular electron bunches as keeping a total current of 100 mA for the other users.

#### **2-2. Femtosecond pulsed laser system**

A femtosecond laser system for irradiation of a GaAs crystal surface has been installed in the experimental hutch of the beamline. The laser system is composed of the mode-locked laser oscillator, and a regenerative amplifier to produce laser

pulses with a pulse width of 130 fs and a pulse energy of about 1mJ/pulse. The laser pulses are synchronized with the master oscillator of the storage ring controlling the acceleration timing of the electron bunches. (See ref. 2)

### **3. Experimental procedure**

#### ***(1) Set up for diffraction measurement of GaAs single crystal.***

In order to observe the 400-Bragg reflection of a GaAs wafer, set the sample on the goniometer, and find the Bragg reflection with an ion chamber.

#### ***(2) Alignment of a femtosecond laser beam onto the sample.***

Guide the femtosecond laser beam onto the sample surface so as to achieve the spatial overlap with the SR beam whose footprint is observed by a burned paper.

#### ***(3) Monitor of the synchronization between the laser pulse and the SR pulse.***

An avalanche photodiode is used to monitor the timing of the laser and the SR pulses. Tune the pulse timing of the laser to be close to the target SR pulse as monitoring with an oscilloscope. Then, adjust the timing of electric gate to cover the target SR pulse signal.

#### ***(4) Control of the timing delay between the pulses.***

Scan the timing of the trigger signal for the femtosecond laser by an electronic circuit including a phase shifter. (See ref. 3) Then you can obtain the diffraction intensity dependent on the delay timing.

#### ***(5) Repetition control with an X-ray pulse selector***

The repetition rate control of incident X-ray beam enable us to use detectors without high time-resolution such as an imaging plate, a CCD camera etc. (See ref. 4). The time-dependent diffraction intensity measurement is also demonstrated by using a PIN photodetector with current mode.

### **4. Expected results**

The diffracted X-ray intensity becomes large with a response time of about a few hundred ps at the smaller angle side of the Bragg diffraction profile, due to the Bragg peak shift. (See refs. of 5 and 6)

### **5. References**

- (1) [http://www.spring8.or.jp/wkg/BL19LXU/instrument/lang-en/INS-0000000361/instrument\\_summary\\_view](http://www.spring8.or.jp/wkg/BL19LXU/instrument/lang-en/INS-0000000361/instrument_summary_view)
- (2) Y. Tanaka *et al.*, Rev. Sci. Instrum., **71**, p.1268 (2000), "Timing control of an intense picosecond laser to the SPring-8 synchrotron radiation pulses"
- (3) Y. Fukuyama *et al.*, Rev. Sci. Instrum., **79**, p.045107 (2008), "Ultra-high-precision time control system over any long time delay for laser"

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- (4) Y. Tanaka *et al.*, Jpn. J. Appl. Phys., 48, p.03A001, (2009). “Development of picoseconds time-resolved microbeam x-ray diffraction technique for investigation of optical recording process”
  - (5) Y. Tanaka *et al.*, J. Synchrotron Rad., **9**, p.96 (2002), “Optical-switching of X-rays using laser-induced lattice expansion”
  - (6) Y. Hayashi *et al.*, Phys. Rev. Lett., **96**, p.115505 (2006), “Acoustic pulse echoes probed with time-resolved x-ray triple-crystal diffractometry”